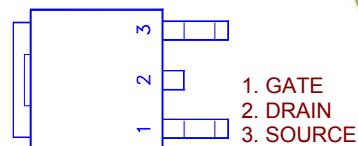
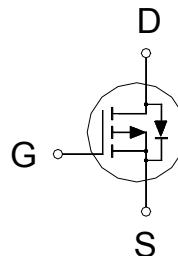


NIKO-SEM
**N-Channel Logic Level Enhancement
Mode Field Effect Transistor**
P2904BD
TO-252
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
40V	29mΩ	25A

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	40	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	25	A
		20	
Pulsed Drain Current ¹	I_{DM}	75	
Avalanche Current	I_{AS}	27	
Avalanche Energy ²	E_{AS}	37	mJ
Power Dissipation	P_D	30	W
		20	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		4.1	°C / W
Junction-to-Ambient	$R_{\theta JA}$		40	°C / W

¹Pulse width limited by maximum junction temperature.
ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ C$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	40			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2	2.4	3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 250	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 32V, V_{GS} = 0V$			1	μA
		$V_{DS} = 30V, V_{GS} = 0V, T_J = 125^\circ C$			10	
On-State Drain Current ¹	$I_{D(ON)}$	$V_{DS} = 5V, V_{GS} = 10V$	75			A

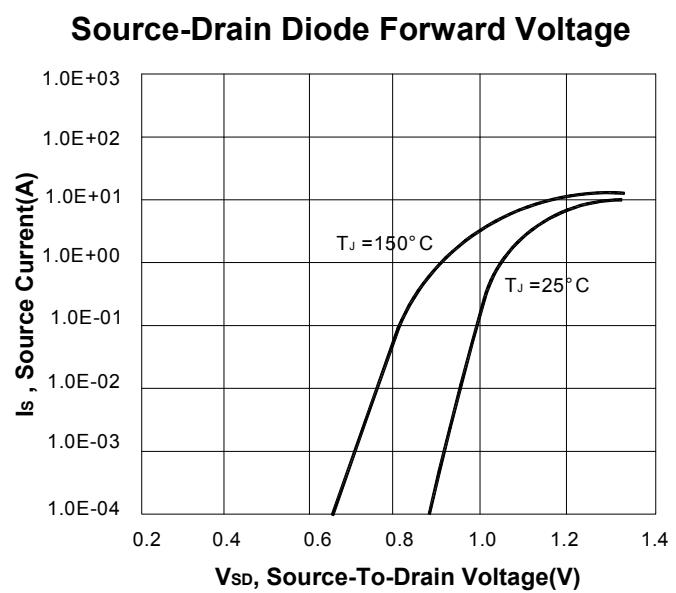
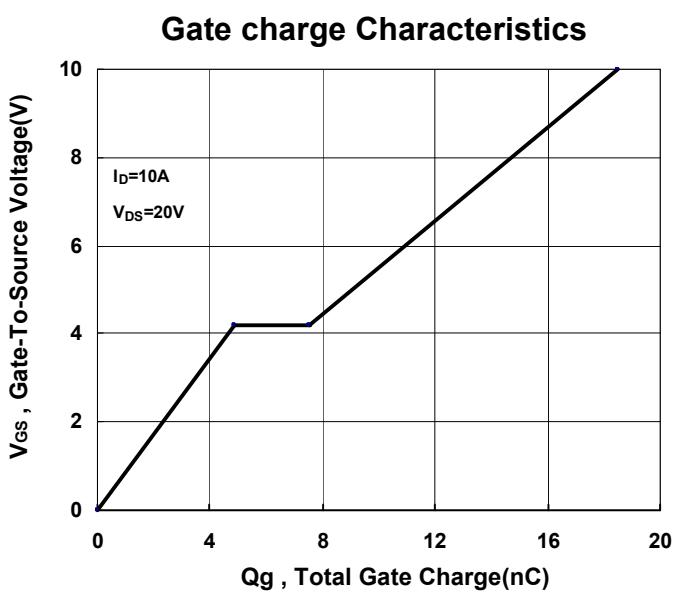
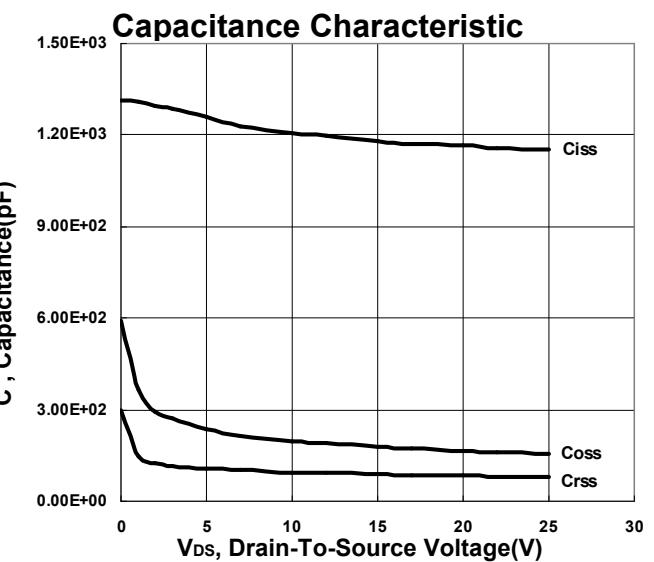
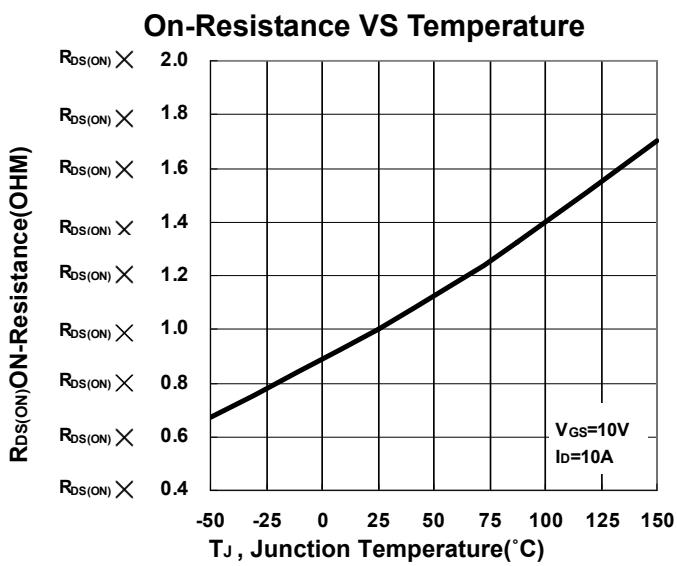
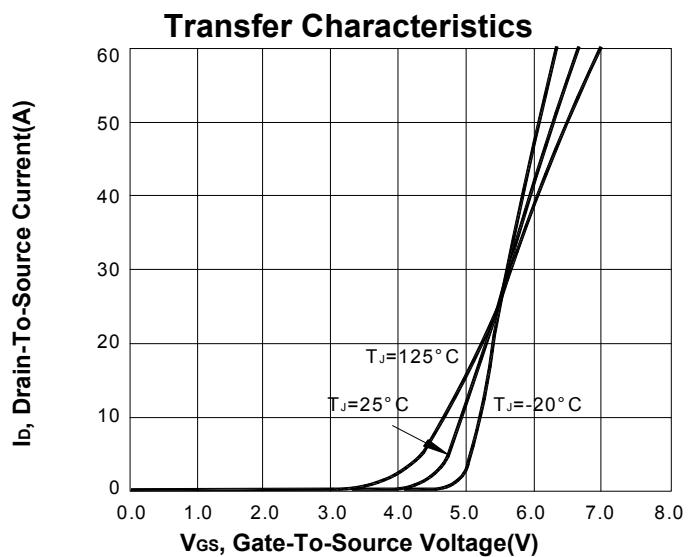
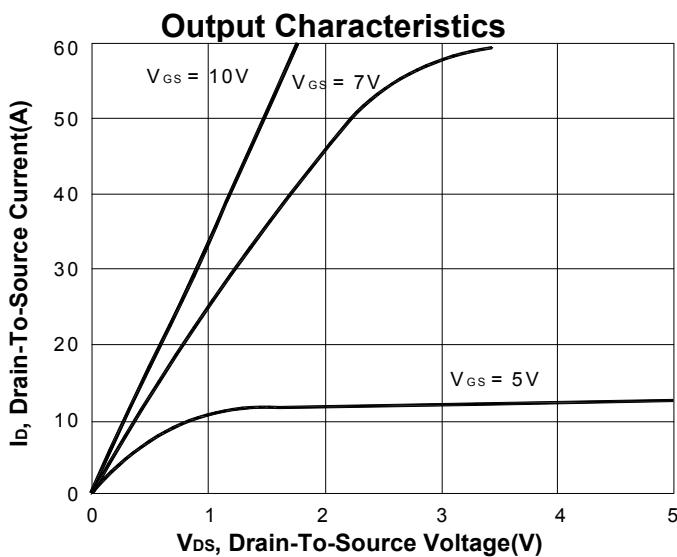
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Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = 5V, I _D = 8A		26	50	mΩ
		V _{GS} = 7V, I _D = 8A		22	45	
		V _{GS} = 10V, I _D = 10A		19	29	
Forward Transconductance ¹	g _{fs}	V _{DS} = 5V, I _D = 10A		30		S
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = 20V, f = 1MHz		1150		pF
Output Capacitance	C _{oss}			157		
Reverse Transfer Capacitance	C _{rss}			80		
Total Gate Charge ²	Q _g (V _{GS} = 10V)	V _{DS} = 0.5V _{(BR)DSS} , I _D = 10A		19		nC
Total Gate Charge ²	Q _g (V _{GS} = 4.5V)			9		
Gate-Source Charge ²	Q _{gs}			4.5		
Gate-Drain Charge ²	Q _{gd}			3		
Gate Resistance	R _g	V _{GS} = 0V, V _{DS} = 0V, f = 1MHz		1.55		Ω
Turn-On Delay Time ²	t _{d(on)}	V _{DS} = 20V, R _L = 1Ω I _D ≈ 1A, V _{GS} = 10V, R _{GS} = 6Ω		10		nS
Rise Time ²	t _r			6		
Turn-Off Delay Time ²	t _{d(off)}			26		
Fall Time ²	t _f			6		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_J = 25 °C)						
Continuous Current	I _S				23	A
Forward Voltage ¹	V _{SD}	I _F = 10A, V _{GS} = 0V			1.3	V
Reverse Recovery Time	t _{rr}	I _F = 10A, dI _F /dt = 100A /μS		38		nS
Reverse Recovery Charge	Q _{rr}			29		nC

¹Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.²Independent of operating temperature.

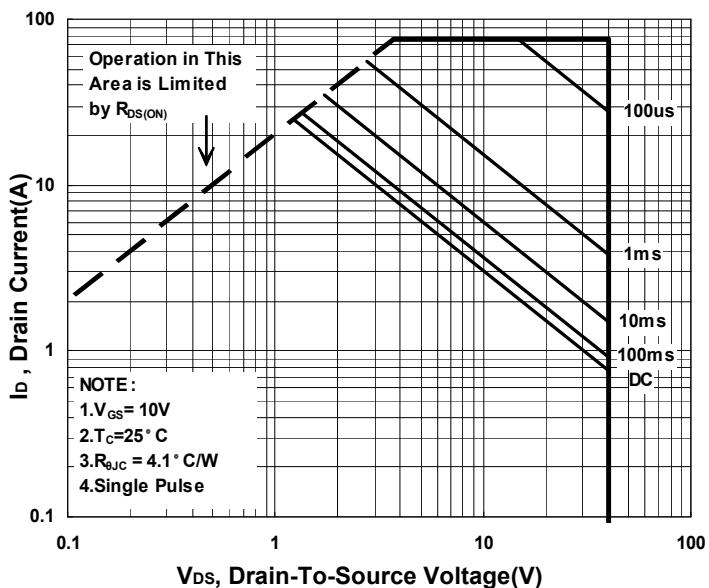
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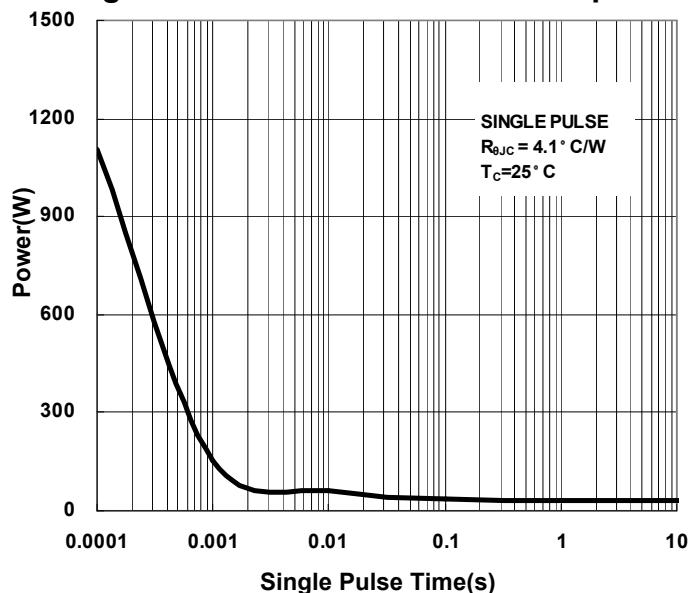
**N-Channel Logic Level Enhancement
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Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

